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| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination FUNAKOSHI ET AL. | |
| | | Examiner Amr Awad | Art Unit 2675 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| | A | US-6,611,249 B1 | 08-2003 | Evanicky et al. | 345/102 |
| | B | US-6,256,425 B1 | 07-2001 | Kunzman, Adam | 382/274 |
| | C | US-5,638,117 a | 06-1997 | Engeldrum et al. | 348/179 |
| | D | US-5,663,770 a | 09-1997 | Yamade, Shigemitsu | 348/656 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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